

356/456

ISSUE CLASSIFICATION	
Class	Subclass

U.S. UTILITY Patent Application

	O.I.P.E.	PATENT DATE
SCANNED	HKm4 Q.A.	

APPLICATION NO. 09/964211	CONT/PRIOR D F	CLASS 324	SUBCLASS 1	ART UNIT 2858	EXAMINER J. C. ...
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APPLICANTS

Akihiko Ito
Yoshihito Kobayashi
Yoshiyuki Masuo
Tsuyoshi Yamashita

TITLE

Semiconductor device testing apparatus and a test tray for use in the testing apparatus

PTO-2040
12/89

ISSUING CLASSIFICATION												
ORIGINAL				CROSS REFERENCE(S)								
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
INTERNATIONAL CLASSIFICATION												

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<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS		CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed. <input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____ _____			NOTICE OF ALLOWANCE MAILED	
			ISSUE FEE	
			Amount Due	Date Paid
<input type="checkbox"/> The terminal ____months of this patent have been disclaimed.			ISSUE BATCH NUMBER	
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